

Swiss participation in AIDAinnova





AIDAinnova scope

AIDAinnova focusses on Strategic R&D in the pre-TDR phase

- Technology Readiness Levels 2-7
- Not yet experiment-specific: potential to unfold synergies Include some prospective R&D
- competitive call at start of project "Blue Sky", quantum sensors,...

Targeted applications

- Higgs Factories
- ALICE, LHCb LS3 pre-TDR, ATLAS & CMS LS4
- Accelerator-based neutrino experiments
- and others







AIDAinnova: Work Packages







WP5: Depleted Monolithic Active Pixel Sensors

DMAPS development

High rate & radiation: radhard (TID & NIEL) + fast resp. time + fast R/O example: LHC upgrades & FCC

concrete development lines

High granularity:

excellent spatial resolution + (fast + radhard): ex.: Belle II upgrade & future Higgs factory etc.

Foundry line	chips dev. line	charge coll.	high rate & radiation	high granularity	special aim
LFoundry 150 nm	LF-Monopix2	large electrode	х		radhard, robust
LFoundry 150 nm	LF-MPW3/4	large electrode	х	(X)	small pixels
TowerJazz 180 nm	TJ-Monopix2/3	small electrode	(X)	х	Belle II Upgrade
TowerJazz 180 nm	TJ-MALTA2/3	small electrode	х	(X)	low power
LFoundry 110 nm	ARCADIA	small electrode		х	large area, low power
TowerJazz 65 nm	TJ 65	tbd likely small		х	small feature size

WP5 convenors: Sebastian Grinstein (IFAE Barcelona), David-Leon Pohl, NW (Univ. of Bonn)





WP5: PSI activities

- PSI is partner organization in AIDAinnova WP5: Depleted Monolithic Active Pixel Sensors
- Development of radiation tolerant Depleted Monolithic Active Pixel Sensors (DMAPS) for high-rate applications
 - in close collaboration with ETH and UZH
- For future upgrades of the CMS experiment, future collider experiments, in-house experiments and other applications
- Effort started in 2018
- Evaluated different technologies, now following up two (TSI and Lfoundry110) with own submissions
- More information in this <u>Tilman Rohe's talk</u>



Pixel chip in TSI prototype run:

- 4 different pixel sizes
- Discriminator in each pixel with 3 trim bits
- External hold possible (as in R4S chip)

Motic A: Monolithic timing chip

- LF110 nm with back-side implant
- Pulse height and time of arrival is measured
- 5x5 mm² chip with different preamplifier designs





WP6:Timing detectors









WP6: Technologies for 3D and pixelated LGADs

Low Gain Avalanche Diode (LGAD) detectors proposed for timing applications: upgrades of Endcap timing layer in CMS and High Granularity Timing Detector in ATLAS.

- In WP6 pushing for higher segmentation and rad-hardness.
- LGADs with Trench-Isolated trenches (TI-LGAD)
- Resistive AC-Coupled Silicon Detectors (RSD)
 - AC-pad coupled to the resistive n+ via dielectric coupling layer
 - Not segmented gain layer: 100% fill factor
 - Radiation hardness to be evaluated
- Inverse LGAD (iLGAD):
 - multiplication region on the opposite side of the read-out electrodes



3D pixels for timing



The idea is to use a 3D based on trenches instead of columns in order to obtain a more uniform electric/weighting field between electrodes \rightarrow reduction of the dependence of timing on the impact position of particles





Interconnection technologies: wafer-to-wafer

Goal: reduce mass, i.e. thickness of pixel detectors as much as possible while keeping the benefits of the hybrid approach:

- Separate development and optimization of sensors and FE electronics allowing for best performance of FE electronic and sensor.
- Fine pitch interconnection between FE and sensor pixel with about 20 μm pitch.
- Thinning of FE and sensor parts to the minimum. Target is the development of ultra-thin hybrid pixel detectors based on:
 - $50 100 \ \mu\text{m}$ thick pixel sensor on 200 (300) mm CMOS wafers
 - ~20 μ m thick pixel FE chip thickness on 200 (300) mm CMOS



Bonn Uni and IZM





Wafer to wafer: Proof of concept for AIDAInnova

Develop dedicated CMOS Sensor wafer compatible with a pixel FE chip wafer:

- Starting point: passive CMOS sensor development on 200 mm wafer with 110/150 nm process node from Lfoundry
- Use either TimePix3 chip wafers (130 nm on 200 mm wafers) or own FE development on the same wafer as the sensor
- Develop and optimize hybridization process including thinning and interconnection from chip's backside
- Transfer process to more modern feature size pixel chips (65nm or 28 nm on 300 mm wafers) for smaller pixel pitches and faster electronics (long term, not with AIDAinnova)









WP6: ACF for pixel detector hybridization

- Bump bonding in specialized industry is costly / complex
- Alternative process: Anisotropic Conductive Films (ACF)
- Epoxy film for mechanical connection, embedded conductive particles for el. connection

Conductive

Mask-less sensor/ASIC metallization: Electroless Nickel Gold (ENIG) deposition

Sensor

Timepix3

- In-house flip-chip process
- Challenge: Optimization of ACF material and flip-chip process for fine pitch

ACF interconnect scheme Silicon sensor substrate



Conductive micro-particles



Involved groups:

• CERN: Sample preparation (metallisation), flip-chip detector assembly, testing, process optimization

- Conpart: Industrial partner / ACF supplier, R&D on micro particles, ACF characterisation, process optimization
- CNRS-LPNHE: Sensor and teststructure procurement and production, testing
- Outside AidaInnova: DESY (test beam) and Geneva (Support for flip-chip infrastructure)





WP10: Advanced mechanics for tracking and vertex detectors

- Bring to maturity CMOS-compatible Si-µ-channel fab processes
- Exploit additive manufacturing for
 - Ultra-thin metal cooling devices
 - Ceramic (composites?) cooling devices
 - Hydraulic connections and interconnections

- Ultra light structures integrating cooling features
- New approach to (natural) refrigerant fluids for warm and cold applications
- Develop instrumentation for accurate absolute position measurements on very small devices





WP10: AIDA Ultra light 3D printed cold plates @CSEM

- Additive Manufacturing technologies ("3D-printing"):
- standardised and reliable approaches to produce 3D-printed high precision micro-channel cold plates.
- Study Different metallic alloys and ceramic composites
- Investigate the minimum channel cross section attainable for a fixed channel length
- Guidelines toward engineering of the future advanced detector cooling solutions.

- Top Swiss RTO* with strong background (among others) in high precision manufacturing.
- Involved: Additive Manufacturing & Component Reliability group
- Specialist of metal printing
- Laser powder based process
- Minimum size 60-150µm, material dependent
- Minimum gap ~100µm
- Material available/underdevelopment:
 - Stainless steel: 316L, 17-4PH
 - Titanium alloys: Ti-6Al-4V, NiTi (shape memory)
 - Copper based: CuSn10
 - Aluminum based: AlSi12, Scalmalloy
 - INVAR (Fe64Ni36) → Kovar (?)
 - Metal Matrix Composite





*



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Research and Technology organization



Additional material



AIDA

The AIDAinnova call

Another call in FP8 was not obvious

• Followed intensive discussions with EC, incl. actions by the CERN directorate

Targeted Call INFRAINNOV-04-2020: Innovation pilots

HORIZON 2020

- Adressing advanced Integrated Activities (i.e. the AIDA-2020 community)
- which have reached a high level of integration and can focus on joint research: collaborative

Objectives

• Support research infrastructure networks developing and implementing a common strategy/roadmap including technological development required for improving their services through partnership with industry

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• Support incremental innovation and cooperation with industry

Complementarity to ATTRACT (competitive, disruptive)

Increased focus on industrial partners

No Transnational Access

Proposed funding 10 M€ for 4 years

infrastructure: common interest



Felix Sefkow | April 2021





WP6: Interconnection technologies

Metal – Oxide Hybrid Bonding

_	Cu/SiO2
	Cu/SiO2
Bond Interface 1.6 um	e: ERI DBI °

Process:

- SiO2 passivation + Cu pads
- Surface planarization (CMP)
- Surface activation (plasma, chemicals)
- Room temperature bond
- Annealing 150 300°C
- 3D chip stacking: memory chips, image sensors

Motivation for DBI[®]:

- W2W , D2W
- Highest interconnect density: I/O pitch down to 1 μm
- High alignment accuracy
- No bumps, no intermetallics
- No gap no underfilling

nG IZM ASSID (Results) 0,146 nm

0,163 nm

5nm @ 100µm

High reliability

Fraunhofer IZM-ASSID: 300mm W2W Bonding with <5µm alignment accuracy

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J. Wolf "3D System Integration Requirements and Potential Solutions", European 3D Summit, 22-24.1.2018, Dresden, Germany.

Fraunhofer test chip with 4 μ m pad /18 μ m pitch, Metal density: 4.5%

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€ . € € ⁰	Roughness on TSV (Cu) Ra	
	Planarization	

Surface preparation in nanometer range \rightarrow Atomic force microscopy





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